

Keysight B2900A Series Precision Source/Measure Unit

For 3-terminal device evaluation such as

- ✓ Laser diodes & photo detectors
- ✓ Field effect transistors
- ✓ Bipolar junction transistors
- ✓ Power transistors
- ✓ Power devices



Model	Description	Qty
B2912A	Precision Source/Measure Unit, 2ch, 10fA resolution, 210V, 3A DC/10.5A pulse	1
N1294A-001	Banana - Triaxial Adapter for 2-wire (non Kelvin) connection	2
16494A-001	Triaxial Cable (1.5m)	4
N1294A-011	1.5m, Interlock cable for 16442A/B test fixture	1

B2912A



N1294A-001¹ (for Ch1)



16494A-001



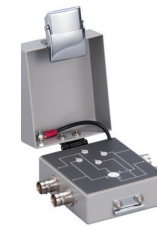
N1294A-001¹ (for Ch2)



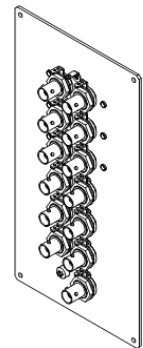
N1294A-011² (for interlock)



Available device test fixtures:



N1295A
For discrete device characterization
at voltages up to 42 V



Wafer Prober
Connector Plate
(For wafer level
characterization)



16442B
For discrete device characterization
at voltages up to 200 V

1. N1294A-001 converts banana to triaxial
2. N1294A-011 is not needed for the N1295A

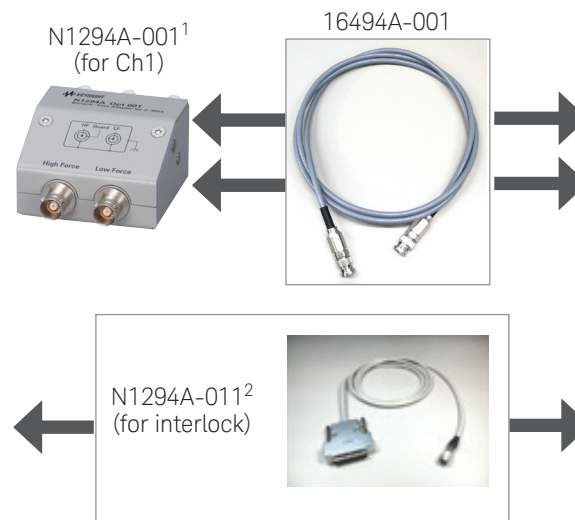
For 2-terminal device evaluation such as

- ✓ Diodes, LEDs
- ✓ Photo detectors, sensors
- ✓ Resistors, varistors, thermistors
- ✓ Photovoltaic cells
- ✓ Nano devices (e.g. CNT)



Model	Description	Qty
B2911A	Precision Source/Measure Unit, 1ch, 10fA resolution, 210V, 3A DC/10.5A pulse	1
N1294A-001	Banana - Triaxial Adapter for 2-wire (non Kelvin) connection	1
16494A-001	Triaxial Cable (1.5m)	2
N1294A-011	1.5m, Interlock cable for 16442A/B test fixture	1

B2911A



1. N1294A-001 converts banana to triaxial
2. N1294A-011 is not needed for the N1295A

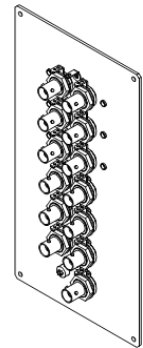
Available device test fixtures:



N1295A
For discrete device characterization
at voltages up to 42 V



16442B
For discrete device characterization
at voltages up to 200 V



Wafer Prober
Connector Plate
(For wafer level
characterization)

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www.keysight.com/find/mykeysight

A personalized view into the information most relevant to you.

For more detail about B2900A series:

www.keysight.com/find/precisionSMU

For more detail about the configuration:

<http://literature.cdn.keysight.com/litweb/pdf/5992-0660EN.pdf>



Unlocking Measurement Insights